

RELIABILITY MONITOR

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|----------------|---------------------|------------------|--------------------------|------------------------|---------------------|---------------------|
| PRODUCT | MONITOR DATE | DATE CODE | ASSEMBLY FACILITY | ASSEMBLY LOT NO | PROCESS TYPE | PACKAGE TYPE |
| DS1267 | Jan-97 | 9644 A1 | ANAM, K. | DN633466AAB | 1.2μ OX/NI | 16 SOIC |

STRESS/JOB NO.

READPOINT

(Sample Size/No. of Fails)

Preconditioning (P/C):
HTC Vapor Phase
P-18967

| | |
|-------------------|--------------|
| <u>Electrical</u> | <u>Cum %</u> |
| 234/0 | 0.0% |

Sonoscan
P-19049

| |
|-------------------------|
| <u>Post Vapor Phase</u> |
| 4/0 |

| | | | | |
|----------------------------|--------------|---------------|--------------|----------------------|
| Infant / High Voltage Life | <u>48 Hr</u> | <u>336 Hr</u> | <u>1K Hr</u> | <u>*Failure Rate</u> |
| 125°C, -4.0 & +6.0 V | 230/0 | 77/0 | 77/0 | 82 Fits |
| P-19050, P-19123 | | | | |

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

| | | | |
|-----------------|--------------|-------------|--------------|
| Temp Cycle | <u>300 ~</u> | <u>1K ~</u> | <u>Cum %</u> |
| -55°C to +125°C | 38/0 | 38/0 | 0.0% |
| P-19124 | | | |

| | | | |
|---------------------|---------------|---------------|--------------|
| Biased Moisture | <u>274 Hr</u> | <u>959 Hr</u> | <u>Cum %</u> |
| 85°C/85% RH, 5.5 V. | 77/0 | 77/0 | 0.0% |
| P-19125 | | | |

| | | |
|------------------------|---------------|--------------|
| Autoclave | <u>168 Hr</u> | <u>Cum %</u> |
| 121°C/100% RH, 2 Atmos | 38/0 | 0.0% |
| P-19126 | | |

Failure Mode

Failure Analysis